

PROGRAM OF THE WEEK

Tuesday 09th

09:00 REGISTRATION

10:30 Electron-Matter Interaction
and generated signals
R. Balboni

11:30 SEM the Instrument and
Working Principles
R. Ciancio

12:30 Electron Sources, Optics,
Lenses and Aberrations
P. Mengucci

13:30 LUNCH

14:30 Detectors and
Image Formation
V. Morandi

15:30 SEM Performances and
Optimization
M. Vittori-Antisari

16:30 COFFEE BREAK

17:00 SPONSORS
PRESENTATIONS

18:00

Wednesday 10th

09:00 EDX Microanalysis
A. Montone

10:00 Low Energy STEM Image
Formation and Detection
V. Morandi

11:00 COFFEE BREAK

11:30 Introduction to
Focused Ion Beam
G. Gazzadi

12:30 Tomography in the SEM
M. Ferroni

13:30 LUNCH

14:30 EBIC – Principles and applications
to device diagnostics
M. Vanzi

15:30 Scanning Electron Microscopy
in Failure Analysis
G. Mura

16:30 COFFEE BREAK

17:00 SPONSORS
PRESENTATIONS

18:00

Thursday 11th

10:00 PRACTICAL SESSIONS
SEM, FIB

11:30 COFFEE BREAK

12:00 PRACTICAL SESSIONS
SEM, FIB

13:30 LUNCH

14:30 PRACTICAL SESSIONS
SEM, FIB

16:00 COFFEE BREAK

16:30 PRACTICAL SESSIONS
SEM, FIB

18:00

Friday 12th

09:30 PRACTICAL SESSIONS
SEM, FIB

11:00 COFFEE BREAK

11:30 PRACTICAL SESSIONS
SEM, FIB

13:00 ROUND TABLE DISCUSSION

13:30 LUNCH